



Welcome to **E-XFL.COM**

Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	384
Number of Logic Elements/Cells	1728
Total RAM Bits	32768
Number of I/O	98
Number of Gates	57906
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv50-6tq144c

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99-02/99	1.2-1.3	Both versions updated package drawings and specs.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43.
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified "Pins not listed" statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	 Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices. Corrected Units column in table under IOB Input Switching Characteristics. Added values to table under CLB SelectRAM Switching Characteristics.
10/00	2.4	 Corrected Pinout information for devices in the BG256, BG432, and BG560 packages in Table 18. Corrected BG256 Pin Function Diagram.
04/01	2.5	 Revised minimums for Global Clock Set-Up and Hold for LVTTL Standard, with DLL. Converted file to modularized format. See Virtex Data Sheet section.
03/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs: Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs: Functional Description (Module 2)

- DS003-3, Virtex 2.5V FPGAs: DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs: Pinout Tables (Module 4)

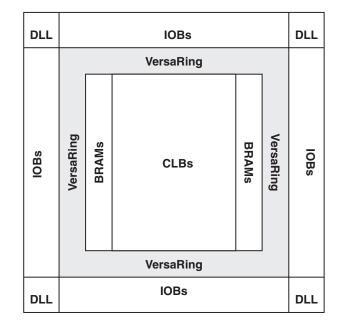


DS003-2 (v4.0) March 1, 2013

Virtex[™] 2.5 V Field Programmable Gate Arrays

Product Specification

The output buffer and all of the IOB control signals have independent polarity controls.



vao_b.eps

Figure 1: Virtex Architecture Overview

All pads are protected against damage from electrostatic discharge (ESD) and from over-voltage transients. Two forms of over-voltage protection are provided, one that permits 5 V compliance, and one that does not. For 5 V compliance, a Zener-like structure connected to ground turns on when the output rises to approximately 6.5 V. When PCI 3.3 V compliance is required, a conventional clamp diode is connected to the output supply voltage, $V_{\rm CCO}$.

Optional pull-up and pull-down resistors and an optional weak-keeper circuit are attached to each pad. Prior to configuration, all pins not involved in configuration are forced into their high-impedance state. The pull-down resistors and the weak-keeper circuits are inactive, but inputs can optionally be pulled up.

The activation of pull-up resistors prior to configuration is controlled on a global basis by the configuration mode pins. If the pull-up resistors are not activated, all the pins will float. Consequently, external pull-up or pull-down resistors must be provided on pins required to be at a well-defined logic level prior to configuration.

All Virtex IOBs support IEEE 1149.1-compatible boundary scan testing.

Architectural Description

Virtex Array

The Virtex user-programmable gate array, shown in Figure 1, comprises two major configurable elements: configurable logic blocks (CLBs) and input/output blocks (IOBs).

- CLBs provide the functional elements for constructing logic
- IOBs provide the interface between the package pins and the CLBs

CLBs interconnect through a general routing matrix (GRM). The GRM comprises an array of routing switches located at the intersections of horizontal and vertical routing channels. Each CLB nests into a VersaBlock™ that also provides local routing resources to connect the CLB to the GRM.

The VersaRing[™] I/O interface provides additional routing resources around the periphery of the device. This routing improves I/O routability and facilitates pin locking.

The Virtex architecture also includes the following circuits that connect to the GRM.

- Dedicated block memories of 4096 bits each
- Clock DLLs for clock-distribution delay compensation and clock domain control
- 3-State buffers (BUFTs) associated with each CLB that drive dedicated segmentable horizontal routing resources

Values stored in static memory cells control the configurable logic elements and interconnect resources. These values load into the memory cells on power-up, and can reload if necessary to change the function of the device.

Input/Output Block

The Virtex IOB, Figure 2, features SelectIO™ inputs and outputs that support a wide variety of I/O signalling standards, see Table 1.

The three IOB storage elements function either as edge-triggered D-type flip-flops or as level sensitive latches. Each IOB has a clock signal (CLK) shared by the three flip-flops and independent clock enable signals for each flip-flop.

In addition to the CLK and CE control signals, the three flip-flops share a Set/Reset (SR). For each flip-flop, this signal can be independently configured as a synchronous Set, a synchronous Reset, an asynchronous Preset, or an asynchronous Clear.

© 1999-2013 Xilinx, Inc. All rights reserved. All Xilinx trademarks, registered trademarks, patents, and disclaimers are as listed at http://www.xilinx.com/legal.htm.
All other trademarks and registered trademarks are the property of their respective owners. All specifications are subject to change without notice.



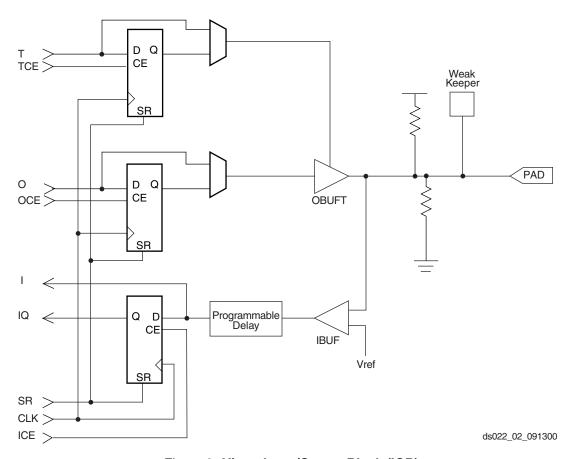


Figure 2: Virtex Input/Output Block (IOB)

Table 1: Supported Select I/O Standards

I/O Standard	Input Reference Voltage (V _{REF})	Output Source Voltage (V _{CCO})	Board Termination Voltage (V _{TT})	5 V Tolerant
LVTTL 2 – 24 mA	N/A	3.3	N/A	Yes
LVCMOS2	N/A	2.5	N/A	Yes
PCI, 5 V	N/A	3.3	N/A	Yes
PCI, 3.3 V	N/A	3.3	N/A	No
GTL	0.8	N/A	1.2	No
GTL+	1.0	N/A	1.5	No
HSTL Class I	0.75	1.5	0.75	No
HSTL Class III	0.9	1.5	1.5	No
HSTL Class IV	0.9	1.5	1.5	No
SSTL3 Class I &II	1.5	3.3	1.5	No
SSTL2 Class I & II	1.25	2.5	1.25	No
CTT	1.5	3.3	1.5	No
AGP	1.32	3.3	N/A	No

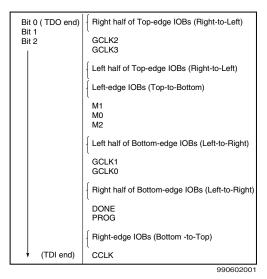


Figure 11: Boundary Scan Bit Sequence

Table 5: Boundary Scan Instructions

Boundary-Scan Command	Binary Code(4:0)	Description
EXTEST	00000	Enables boundary-scan EXTEST operation
SAMPLE/PRELOAD	00001	Enables boundary-scan SAMPLE/PRELOAD operation
USER 1	00010	Access user-defined register 1
USER 2	00011	Access user-defined register 2
CFG_OUT	00100	Access the configuration bus for read operations.
CFG_IN	00101	Access the configuration bus for write operations.
INTEST	00111	Enables boundary-scan INTEST operation
USERCODE	01000	Enables shifting out USER code
IDCODE	01001	Enables shifting out of ID Code
HIGHZ	01010	3-states output pins while enabling the Bypass Register
JSTART	01100	Clock the start-up sequence when StartupClk is TCK
BYPASS	11111	Enables BYPASS
RESERVED	All other codes	Xilinx reserved instructions

Identification Registers

The IDCODE register is supported. By using the IDCODE, the device connected to the JTAG port can be determined.

The IDCODE register has the following binary format:

vvvv:ffff:fffa:aaaa:aaaa:cccc:cccc1

where

v = the die version number

f = the family code (03h for Virtex family)

a = the number of CLB rows (ranges from 010h for XCV50 to 040h for XCV1000)

c = the company code (49h for Xilinx)

The USERCODE register is supported. By using the USER-CODE, a user-programmable identification code can be loaded and shifted out for examination. The identification code is embedded in the bitstream during bitstream generation and is valid only after configuration.

Table 6: IDCODEs Assigned to Virtex FPGAs

FPGA	IDCODE
XCV50	v0610093h
XCV100	v0614093h
XCV150	v0618093h
XCV200	v061C093h
XCV300	v0620093h
XCV400	v0628093h
XCV600	v0630093h
XCV800	v0638093h
XCV1000	v0640093h

Including Boundary Scan in a Design

Since the boundary scan pins are dedicated, no special element needs to be added to the design unless an internal data register (USER1 or USER2) is desired.

If an internal data register is used, insert the boundary scan symbol and connect the necessary pins as appropriate.

Development System

Virtex FPGAs are supported by the Xilinx Foundation and Alliance CAE tools. The basic methodology for Virtex design consists of three interrelated steps: design entry, implementation, and verification. Industry-standard tools are used for design entry and simulation (for example, Synopsys FPGA Express), while Xilinx provides proprietary architecture-specific tools for implementation.

The Xilinx development system is integrated under the Xilinx Design Manager (XDM™) software, providing design-



Date	Version	Revision
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified "Pins not listed" statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	 Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices. Corrected Units column in table under IOB Input Switching Characteristics. Added values to table under CLB SelectRAM Switching Characteristics.
10/00	2.4	 Corrected Pinout information for devices in the BG256, BG432, and BG560 packages in Table 18. Corrected BG256 Pin Function Diagram.
04/01	2.5	 Revised minimums for Global Clock Set-Up and Hold for LVTTL Standard, with DLL. Updated SelectMAP Write Timing Characteristics values in Table 9. Converted file to modularized format. See the Virtex Data Sheet section.
07/19/01	2.6	Made minor edits to text under Configuration.
07/19/02	2.7	Made minor edit to Figure 16 and Figure 18.
09/10/02	2.8	Added clarifications in the Configuration, Boundary-Scan Mode, and Block SelectRAM sections. Revised Figure 17.
12/09/02	2.8.1	 Added clarification in the Boundary Scan section. Corrected number of buffered Hex lines listed in General Purpose Routing section.
03/01/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs: Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs: Functional Description (Module 2)

- DS003-3, Virtex 2.5V FPGAs:
 DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs: Pinout Tables (Module 4)



Virtex[™] 2.5 V Field Programmable Gate Arrays

DS003-3 (v4.0) March 1, 2013

Production Product Specification

Virtex Electrical Characteristics Definition of Terms

Electrical and switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance: These speed files are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary: These speed files are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production: These speed files are released once enough production silicon of a particular device family member has been characterized to provide full correlation between speed files and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications. Contact the factory for design considerations requiring more detailed information.

Table 1 correlates the current status of each Virtex device with a corresponding speed file designation.

Table 1: Virtex Device Speed Grade Designations

	Speed Grade Designations							
Device	Advance	Preliminary	Production					
XCV50			-6, -5, -4					
XCV100			-6, -5, -4					
XCV150			-6, -5, -4					
XCV200			-6, -5, -4					
XCV300			-6, -5, -4					
XCV400			-6, -5, -4					
XCV600			-6, -5, -4					
XCV800			-6, -5, -4					
XCV1000			-6, -5, -4					

All specifications are subject to change without notice.



Virtex Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation net list. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Virtex devices unless otherwise noted.

IOB Input Switching Characteristics

Input delays associated with the pad are specified for LVTTL levels. For other standards, adjust the delays with the values shown in , page 6.

				Speed	Grade		
Description	Device	Symbol	Min	-6	-5	-4	Units
Propagation Delays							
Pad to I output, no delay	All	T _{IOPI}	0.39	0.8	0.9	1.0	ns, max
Pad to I output, with delay	XCV50	T _{IOPID}	0.8	1.5	1.7	1.9	ns, max
	XCV100		0.8	1.5	1.7	1.9	ns, max
	XCV150		0.8	1.5	1.7	1.9	ns, max
	XCV200		0.8	1.5	1.7	1.9	ns, max
	XCV300		0.8	1.5	1.7	1.9	ns, max
	XCV400		0.9	1.8	2.0	2.3	ns, max
	XCV600		0.9	1.8	2.0	2.3	ns, max
	XCV800		1.1	2.1	2.4	2.7	ns, max
	XCV1000		1.1	2.1	2.4	2.7	ns, max
Pad to output IQ via transparent latch, no delay	All	T _{IOPLI}	0.8	1.6	1.8	2.0	ns, max
Pad to output IQ via transparent	XCV50	T _{IOPLID}	1.9	3.7	4.2	4.8	ns, max
latch, with delay	XCV100		1.9	3.7	4.2	4.8	ns, max
	XCV150		2.0	3.9	4.3	4.9	ns, max
	XCV200		2.0	4.0	4.4	5.1	ns, max
	XCV300		2.0	4.0	4.4	5.1	ns, max
	XCV400		2.1	4.1	4.6	5.3	ns, max
	XCV600		2.1	4.2	4.7	5.4	ns, max
	XCV800		2.2	4.4	4.9	5.6	ns, max
	XCV1000		2.3	4.5	5.1	5.8	ns, max
Sequential Delays			·				
Clock CLK	All						
Minimum Pulse Width, High		T _{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low		T _{CL}	0.8	1.5	1.7	2.0	ns, min
Clock CLK to output IQ		T _{IOCKIQ}	0.2	0.7	0.7	8.0	ns, max



Calculation of T_{ioop} as a Function of Capacitance

 T_{ioop} is the propagation delay from the O Input of the IOB to the pad. The values for T_{ioop} were based on the standard capacitive load (CsI) for each I/O standard as listed in Table 2.

Table 2: Constants for Calculating T_{ioop}

Standard	Csl (pF)	fl (ns/pF)
LVTTL Fast Slew Rate, 2mA drive	35	0.41
LVTTL Fast Slew Rate, 4mA drive	35	0.20
LVTTL Fast Slew Rate, 6mA drive	35	0.13
LVTTL Fast Slew Rate, 8mA drive	35	0.079
LVTTL Fast Slew Rate, 12mA drive	35	0.044
LVTTL Fast Slew Rate, 16mA drive	35	0.043
LVTTL Fast Slew Rate, 24mA drive	35	0.033
LVTTL Slow Slew Rate, 2mA drive	35	0.41
LVTTL Slow Slew Rate, 4mA drive	35	0.20
LVTTL Slow Slew Rate, 6mA drive	35	0.100
LVTTL Slow Slew Rate, 8mA drive	35	0.086
LVTTL Slow Slew Rate, 12mA drive	35	0.058
LVTTL Slow Slew Rate, 16mA drive	35	0.050
LVTTL Slow Slew Rate, 24mA drive	35	0.048
LVCMOS2	35	0.041
PCI 33MHz 5V	50	0.050
PCI 33MHZ 3.3 V	10	0.050
PCI 66 MHz 3.3 V	10	0.033
GTL	0	0.014
GTL+	0	0.017
HSTL Class I	20	0.022
HSTL Class III	20	0.016
HSTL Class IV	20	0.014
SSTL2 Class I	30	0.028
SSTL2 Class II	30	0.016
SSTL3 Class I	30	0.029
SSTL3 Class II	30	0.016
СТТ	20	0.035
AGP	10	0.037

Notes:

- I/O parameter measurements are made with the capacitance values shown above. See Application Note XAPP133 on <u>www.xilinx.com</u> for appropriate terminations.
- I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.

For other capacitive loads, use the formulas below to calculate the corresponding T_{ioop} .

$$T_{ioop} = T_{ioop} + T_{opadjust} + (C_{load} - C_{sl}) * fl$$

Where:

 $T_{opadjust}$ is reported above in the Output Delay Adjustment section.

C_{load} is the capacitive load for the design.

Table 3: Delay Measurement Methodology

Standard	V _L ⁽¹⁾ V _H ⁽¹⁾		Meas. Point	V _{REF} Typ ⁽²⁾
LVTTL	0	3	1.4	-
LVCMOS2	0	2.5	1.125	-
PCI33_5	Pe	er PCI Spec		-
PCI33_3	Pe	er PCI Spec		-
PCI66_3	Pe	er PCI Spec		-
GTL	V _{REF} -0.2 V _{REF} +0.2		V _{REF}	0.80
GTL+	V _{REF} -0.2	V _{REF} +0.2	V _{REF}	1.0
HSTL Class I	V _{REF} -0.5	V _{REF} +0.5	V _{REF}	0.75
HSTL Class III	V _{REF} -0.5	V _{REF} +0.5	V _{REF}	0.90
HSTL Class IV	V _{REF} -0.5	V _{REF} +0.5	V _{REF}	0.90
SSTL3 I & II	V _{REF} -1.0	V _{REF} +1.0	V _{REF}	1.5
SSTL2 I & II	V _{REF} -0.75	V _{REF} +0.75	V_{REF}	1.25
CTT	V _{REF} -0.2	V _{REF} +0.2	V _{REF}	1.5
AGP	V _{REF} – (0.2xV _{CCO})	V _{REF} + (0.2xV _{CCO})	V _{REF}	Per AGP Spec

Notes:

- Input waveform switches between V_Land V_H.
- 2. Measurements are made at VREF (Typ), Maximum, and Minimum. Worst-case values are reported.
- I/O parameter measurements are made with the capacitance values shown in Table 2. See Application Note XAPP133 on www.xilinx.com for appropriate terminations.
- 4. I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.



I/O Standard Global Clock Input Adjustments

				Speed	Grade		
Description	Symbol	Standard ⁽¹⁾	Min	-6	-5	-4	Units
Data Input Delay Adjustments							
Standard-specific global clock input delay adjustments	T _{GPLVTTL}	LVTTL	0	0	0	0	ns, max
	T _{GPLVCMOS}	LVCMOS2	-0.02	-0.04	-0.04	-0.05	ns, max
	T _{GPPCl33_3}	PCI, 33 MHz, 3.3 V	-0.05	-0.11	-0.12	-0.14	ns, max
	T _{GPPCl33_5}	PCI, 33 MHz, 5.0 V	0.13	0.25	0.28	0.33	ns, max
	T _{GPPCl66_3}	PCI, 66 MHz, 3.3 V	-0.05	-0.11	-0.12	-0.14	ns, max
	T _{GPGTL}	GTL	0.7	0.8	0.9	0.9	ns, max
	T _{GPGTLP}	GTL+	0.7	0.8	0.8	0.8	ns, max
	T _{GPHSTL}	HSTL	0.7	0.7	0.7	0.7	ns, max
	T _{GPSSTL2}	SSTL2	0.6	0.52	0.51	0.50	ns, max
	T _{GPSSTL3}	SSTL3	0.6	0.6	0.55	0.54	ns, max
	T _{GPCTT}	СТТ	0.7	0.7	0.7	0.7	ns, max
	T _{GPAGP}	AGP	0.6	0.54	0.53	0.52	ns, max

Notes:

^{1.} Input timing for GPLVTTL is measured at 1.4 V. For other I/O standards, see Table 3.



DLL Timing Parameters

All devices are 100 percent functionally tested. Because of the difficulty in directly measuring many internal timing parameters, those parameters are derived from benchmark timing patterns. The following guidelines reflect worst-case values across the recommended operating conditions.

		Speed Grade								
		-6		-6		-6 -5		-4		
Description	Symbol	Min	Max	Min	Max	Min	Max	Units		
Input Clock Frequency (CLKDLLHF)	FCLKINHF	60	200	60	180	60	180	MHz		
Input Clock Frequency (CLKDLL)	FCLKINLF	25	100	25	90	25	90	MHz		
Input Clock Pulse Width (CLKDLLHF)	T _{DLLPWHF}	2.0	-	2.4	-	2.4	-	ns		
Input Clock Pulse Width (CLKDLL)	T _{DLLPWLF}	2.5	-	3.0		3.0	-	ns		

Notes:

DLL Clock Tolerance, Jitter, and Phase Information

All DLL output jitter and phase specifications determined through statistical measurement at the package pins using a clock mirror configuration and matched drivers.

			CLKDLLHF		CLKDLL		
Description	Symbol	F _{CLKIN}	Min	Max	Min	Max	Units
Input Clock Period Tolerance	T _{IPTOL}		-	1.0	-	1.0	ns
Input Clock Jitter Tolerance (Cycle to Cycle)	T _{IJITCC}		-	± 150	-	± 300	ps
Time Required for DLL to Acquire Lock	T _{LOCK}	> 60 MHz	ı	20	-	20	μs
		50 - 60 MHz	ı	-	-	25	μs
		40 - 50 MHz	ı	-	-	50	μs
		30 - 40 MHz	ı	-	-	90	μs
		25 - 30 MHz	ı	-	-	120	μs
Output Jitter (cycle-to-cycle) for any DLL Clock Output (1)	T _{OJITCC}			± 60		± 60	ps
Phase Offset between CLKIN and CLKO ⁽²⁾	T _{PHIO}			± 100		± 100	ps
Phase Offset between Clock Outputs on the DLL ⁽³⁾	T _{PHOO}			± 140		± 140	ps
Maximum Phase Difference between CLKIN and CLKO ⁽⁴⁾	T _{PHIOM}			± 160		± 160	ps
Maximum Phase Difference between Clock Outputs on the DLL (5)	T _{PHOOM}			± 200		± 200	ps

Notes:

- 1. Output Jitter is cycle-to-cycle jitter measured on the DLL output clock, excluding input clock jitter.
- Phase Offset between CLKIN and CLKO is the worst-case fixed time difference between rising edges of CLKIN and CLKO, excluding Output Jitter and input clock jitter.
- Phase Offset between Clock Outputs on the DLL is the worst-case fixed time difference between rising edges of any two DLL outputs, excluding Output Jitter and input clock jitter.
- 4. Maximum Phase Difference between CLKIN an CLKO is the sum of Output Jitter and Phase Offset between CLKIN and CLKO, or the greatest difference between CLKIN and CLKO rising edges due to DLL alone (excluding input clock jitter).
- Maximum Phase Difference between Clock Outputs on the DLL is the sum of Output Jitter and Phase Offset between any DLL
 clock outputs, or the greatest difference between any two DLL output rising edges sue to DLL alone (excluding input clock jitter).
- 6. All specifications correspond to Commercial Operating Temperatures (0°C to +85°C).

^{1.} All specifications correspond to Commercial Operating Temperatures (0°C to + 85°C).



Period Tolerance: the allowed input clock period change in nanoseconds.

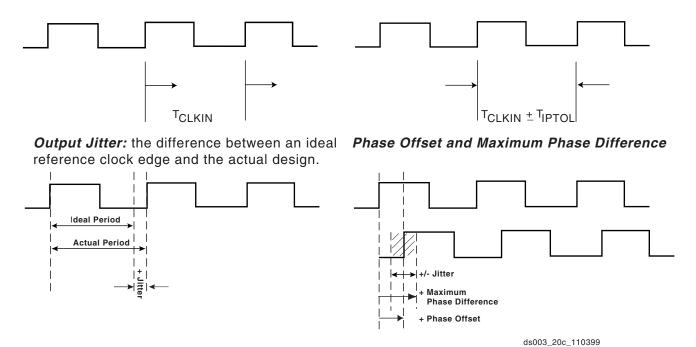


Figure 1: Frequency Tolerance and Clock Jitter

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99	1.2	Updated package drawings and specs.
02/99	1.3	Update of package drawings, updated specifications.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43.



Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages) (Continued)

Pin Name	Device	CS144	TQ144	PQ/HQ240
V _{REF} , Bank 3	XCV50	H11, K12	60, 68	130, 144
(V _{REF} pins are listed	XCV100/150	+ J10	+ 66	+ 133
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 126
the required device	XCV400	N/A	N/A	+ 147
and all smaller devices listed in the same	XCV600	N/A	N/A	+ 132
package.)	XCV800	N/A	N/A	+ 140
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				
V _{REF} , Bank 4	XCV50	L8, L10	79, 87	97, 111
(V _{REF} pins are listed	XCV100/150	+ N10	+ 81	+ 108
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 115
the required device and all smaller devices	XCV400	N/A	N/A	+ 94
listed in the same	XCV600	N/A	N/A	+ 109
package.)	XCV800	N/A	N/A	+ 101
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				
V _{REF} , Bank 5	XCV50	L4, L6	96, 104	70, 84
(V _{REF} pins are listed	XCV100/150	+ N4	+ 102	+ 73
incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.)	XCV200/300	N/A	N/A	+ 66
	XCV400	N/A	N/A	+ 87
	XCV600	N/A	N/A	+ 72
	XCV800	N/A	N/A	+ 80
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				



Table 4: Virtex Pinout Tables (Fine-Pitch BGA)

Pin Name	Device	FG256	FG456	FG676	FG680
GCK0	All	N8	W12	AA14	AW19
GCK1	All	R8	Y11	AB13	AU22
GCK2	All	C9	A11	C13	D21
GCK3	All	B8	C11	E13	A20
M0	All	N3	AB2	AD4	AT37
M1	All	P2	U5	W7	AU38
M2	All	R3	Y4	AB6	AT35
CCLK	All	D15	B22	D24	E4
PROGRAM	All	P15	W20	AA22	AT5
DONE	All	R14	Y19	AB21	AU5
INIT	All	N15	V19	Y21	AU2
BUSY/DOUT	All	C15	C21	E23	E3
D0/DIN	All	D14	D20	F22	C2
D1	All	E16	H22	K24	P4
D2	All	F15	H20	K22	P3
D3	All	G16	K20	M22	R1
D4	All	J16	N22	R24	AD3
D5	All	M16	R21	U23	AG2
D6	All	N16	T22	V24	AH1
D7	All	N14	Y21	AB23	AR4
WRITE	All	C13	A20	C22	B4
CS	All	B13	C19	E21	D5
TDI	All	A15	B20	D22	В3
TDO	All	B14	A21	C23	C4
TMS	All	D3	D3	F5	E36
TCK	All	C4	C4	E6	C36
DXN	All	R4	Y5	AB7	AV37
DXP	All	P4	V6	Y8	AU35



Table 4: Virtex Pinout Tables (Fine-Pitch BGA) (Continued)

Pin Name	Device	FG256	FG456	FG676	FG680
V _{REF} Bank 4	XCV50	P9, T12	N/A	N/A	N/A
(V _{REF} pins are listed incrementally. Connect	XCV100/150	+ T11	AA13, AB16, AB19	N/A	N/A
all pins listed for both the required device and	XCV200/300	+ R13	+ AB20	N/A	N/A
all smaller devices listed in the same package.)	XCV400	N/A	N/A	AC15, AD18, AD21, AD22, AF15	N/A
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV600	N/A	N/A	+ AF20	AT19, AU7, AU17, AV8, AV10, AW11
pins are general i/o.	XCV800	N/A	N/A	+ AF17	+ AV14
	XCV1000	N/A	N/A	N/A	+ AU6
V _{REF} Bank 5	XCV50	T4, P8	N/A	N/A	N/A
(V _{REF} pins are listed	XCV100/150	+ R5	W8, Y10, AA5	N/A	N/A
incrementally. Connect all pins listed for both	XCV200/300	+ T2	+ Y6	N/A	N/A
the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV400	N/A	N/A	AA10, AB8, AB12, AC7, AF12	N/A
	XCV600	N/A	N/A	+ AF8	AT27, AU29, AU31, AV35, AW21, AW23
	XCV800	N/A	N/A	+ AE10	+ AT25
	XCV1000	N/A	N/A	N/A	+ AV36
V _{REF} Bank 6	XCV50	J3, N1	N/A	N/A	N/A
(V _{REF} pins are listed	XCV100/150	+ M1	N2, R4, T3	N/A	N/A
incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage	XCV200/300	+ N2	+ Y1	N/A	N/A
	XCV400	N/A	N/A	AB3, R1, R4, U6, V5	N/A
	XCV600	N/A	N/A	+ Y1	AB35, AD37, AH39, AK39, AM39, AN36
is not required, all V _{REF}	XCV800	N/A	N/A	+ U2	+ AE39
pins are general I/O.	XCV1000	N/A	N/A	N/A	+ AT39



Table 4: Virtex Pinout Tables (Fine-Pitch BGA) (Continued)

Pin Name	Device	FG256	FG456	FG676	FG680
No Connect (No-connect pins are listed incrementally. All pins listed for both the required device and all larger devices listed in the same package are no connects.)	XCV800	N/A	N/A	A2, A3, A15, A25, B1, B6, B11, B16, B21, B24, B26, C1, C2, C25, C26, F2, F6, F21, F25, L2, L25, N25, P2, T2, T25, AA2, AA6, AA21, AA25, AD1, AD2, AD25, AE1, AE3, AE6, AE11, AE14, AE16, AE21, AE24, AE26, AF2, AF24, AF25	N/A
	XCV600	N/A	N/A	same as above	N/A
	XCV400	N/A	N/A	+ A9, A10, A13, A16, A24, AC1, AC25, AE12, AE15, AF3, AF10, AF11, AF13, AF14, AF16, AF18, AF23, B4, B12, B13, B15, B17, D1, D25, H26, J1, K26, L1, M1, M25, N1, N26, P1, P26, R2, R26, T1, T26, U26, V1	N/A
	XCV300	N/A	D4, D19, W4, W19	N/A	N/A
	XCV200	N/A	+ A2, A6, A12, B11, B16, C2, D1, D18, E17, E19, G2, G22, L2, L19, M2, M21, R3, R20, U3, U18, Y22, AA1, AA3, AA11, AA16, AB7, AB12, AB21,	N/A	N/A
	XCV150	N/A	+ A13, A14, C8, C9, E13, F11, H21, J1, J4, K2, K18, K19, M17, N1, P1, P5, P22, R22, W13, W15, AA9, AA10, AB8, AB14	N/A	N/A



BG256 Pin Function Diagram

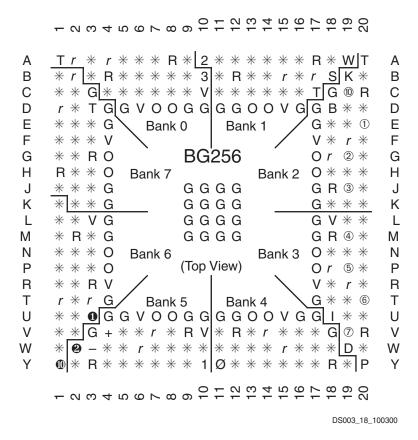
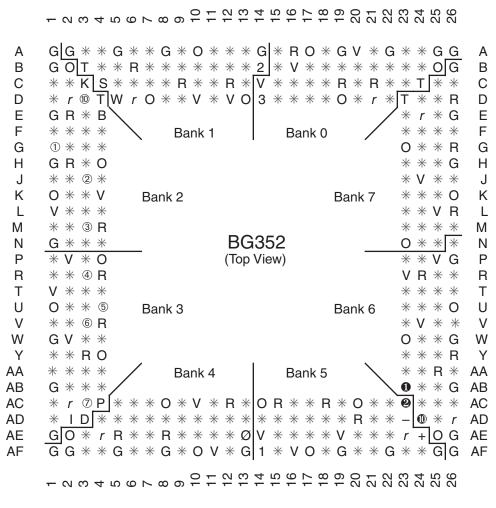


Figure 4: BG256 Pin Function Diagram



BG352 Pin Function Diagram

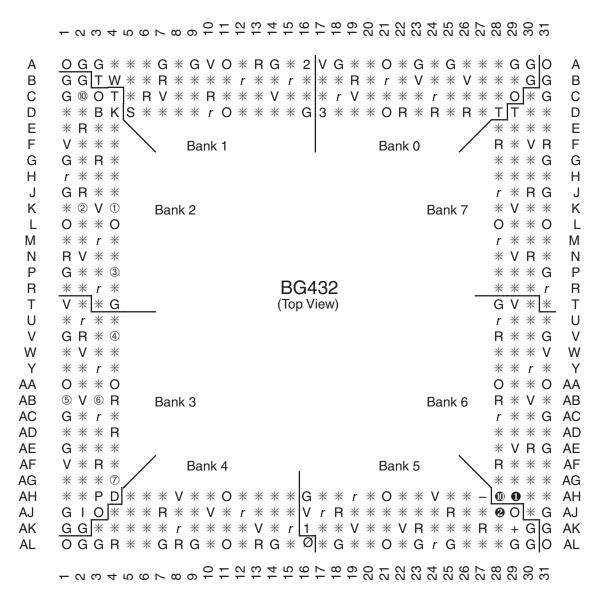


DS003_19_100600

Figure 5: BG352 Pin Function Diagram



BG432 Pin Function Diagram



DS003_21_100300

Figure 6: BG432 Pin Function Diagram



FG256 Pin Function Diagram

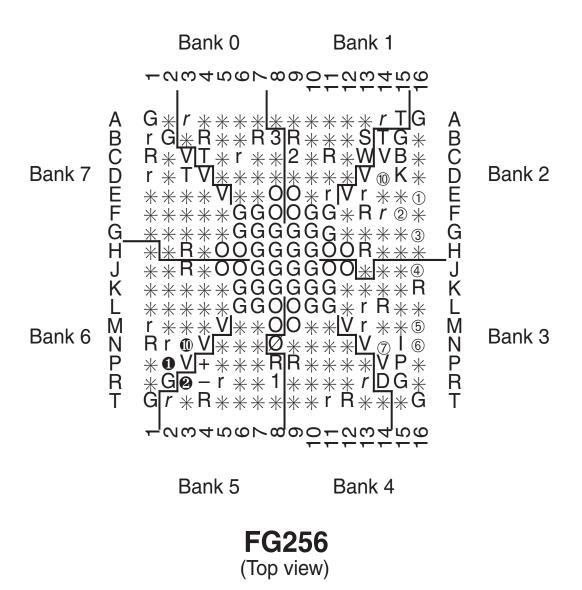


Figure 8: FG256 Pin Function Diagram



FG680 Pin Function Diagram

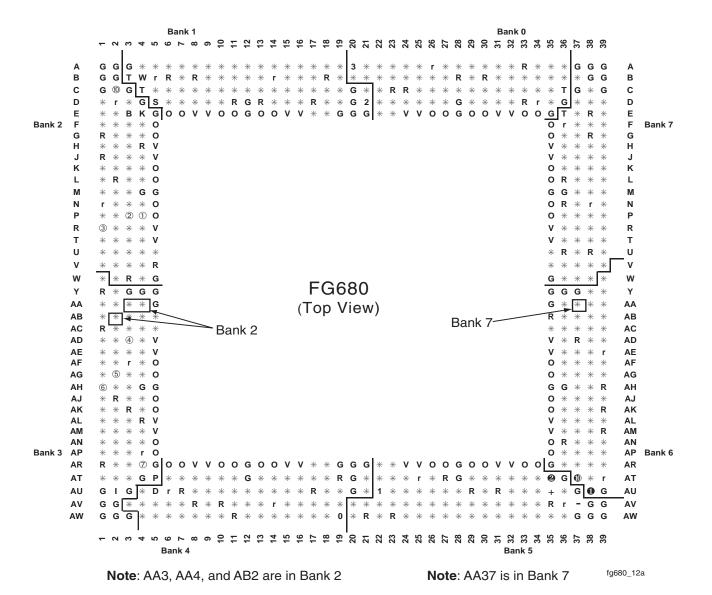


Figure 11: FG680 Pin Function Diagram